

BOARD DESCRIPTION

The AD8353 evaluation board has been carefully laid out and tested to demonstrate the specified high speed performance of the device. Figure 1 shows the schematic of the evaluation board. Note that L1 is shown as an optional component that is used to obtain maximum gain only when $V_p = 3$ V. The board is powered by a single supply in the range 2.7 V to 5.5 V. The power supply is decoupled by a 0.47 μ F and a 100 pF capacitor. For ordering information, please refer to the Ordering Guide.

ORDERING GUIDE

Model	Package Description
AD8353-EVAL	Evaluation Board

Table I. Evaluation Board Configuration Options

Component	Function	Default Value
C1, C2	AC-Coupling Capacitors	1000 pF, 0603
C3	High Frequency Bypass Capacitor	100 pF, 0603
C4	Low Frequency Bypass Capacitor	0.47 μ F, 0603
L1	Optional RF Choke, Used to Increase Current through Output Stage when $V_p = 3$ V. Not recommended for use when $V_p = 5$ V.	100 nH, 0603

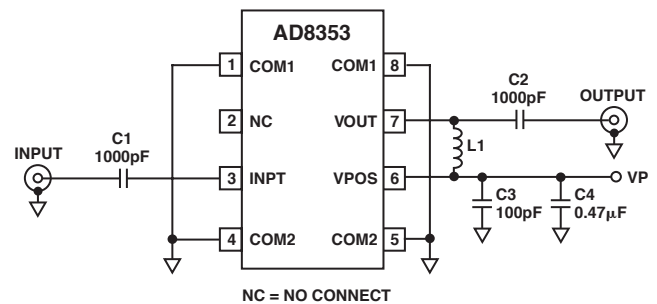


Figure 1. Evaluation Board Schematic

CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although the EVAL-AD8353EB features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



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EVAL-AD8353EB

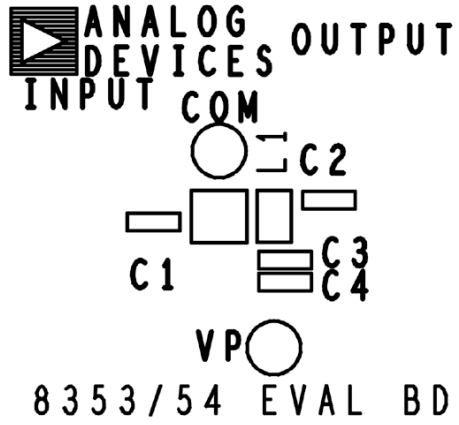


Figure 2. Silkscreen Top

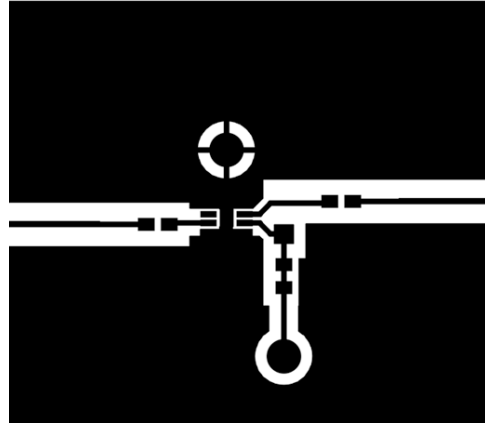


Figure 3. Component Side

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